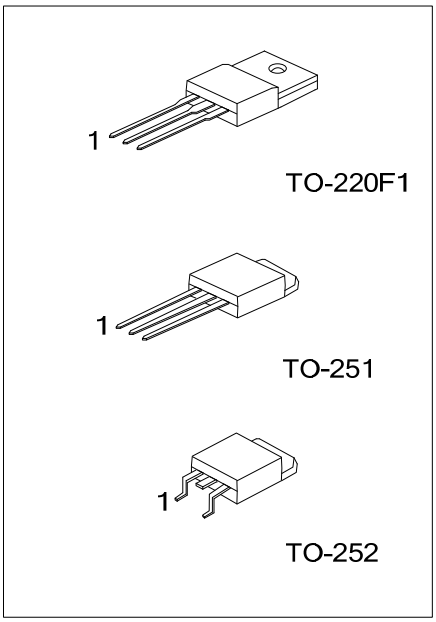
4NM65-U2

Power MOSFET

4A, 650V N-CHANNEL SUPER-JUNCTION MOSFET



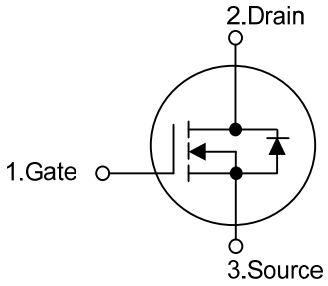
■ DESCRIPTION

The UTC **4NM65-U2** is a Super Junction MOSFET Structure and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche characteristics. This power MOSFET is usually used in high speed switching applications at power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

■ FEATURES

* $R_{DS(ON)}$ < 2.1Ω @ V_{GS} =10V, I_D = 2.0 A
* Fast Switching Capability
* Improved dv/dt Capability, High Ruggedness

■ SYMBOL



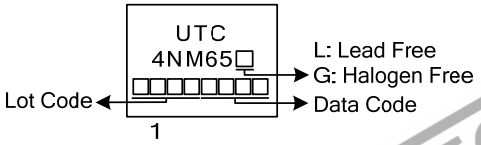
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
4NM65L-TF1-T	4NM65G-TF1-T	TO-220F1	G	D	S	Tube
4NM65L-TM3-T	4NM65G-TM3-T	TO-251	G	D	S	Tube
4NM65L-TN3-R	4NM65G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

4NM65G-TF1-T (1)Packing Type (2)Package Type (3)Green Package	(1) T: Tube, R: Tape Reel (2) TF1: TO-220F1, TM3: TO-251, TN3: TO-252 (3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	650	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous	I_D	4	A
	Pulsed (Note 2)	I_{DM}	16	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	116	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4	V/ns
Power Dissipation	TO-220F1	P_D	36	W
	TO-251/TO-252		50	W
Junction Temperature		T_J	+150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L=144mH, I_{AS}=1.27A, V_{DD}=50V, R_G=25 Ω, Starting T_J = 25°C
4. I_{SD}≤4.0A, di/dt≤200A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

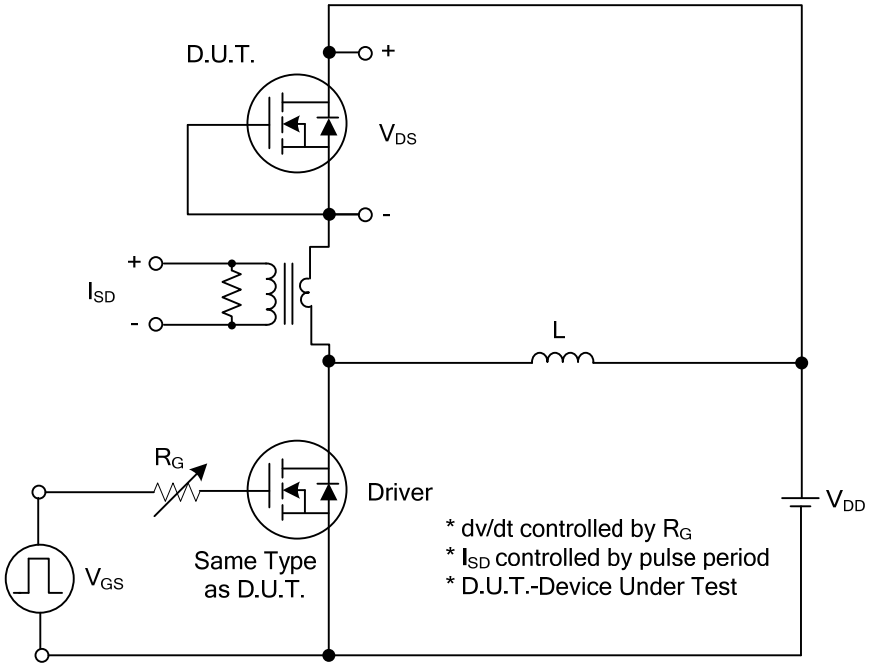
PARAMETER		SYMBOL	RATING	UNIT
Junction to Ambient	TO-220F1	θ_{JA}	62.5	°C/W
	TO-251/TO-252		110	°C/W
Junction to Case	TO-220F1	θ_{JC}	3.67	°C/W
	TO-251/TO-252		2.5	°C/W

■ ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

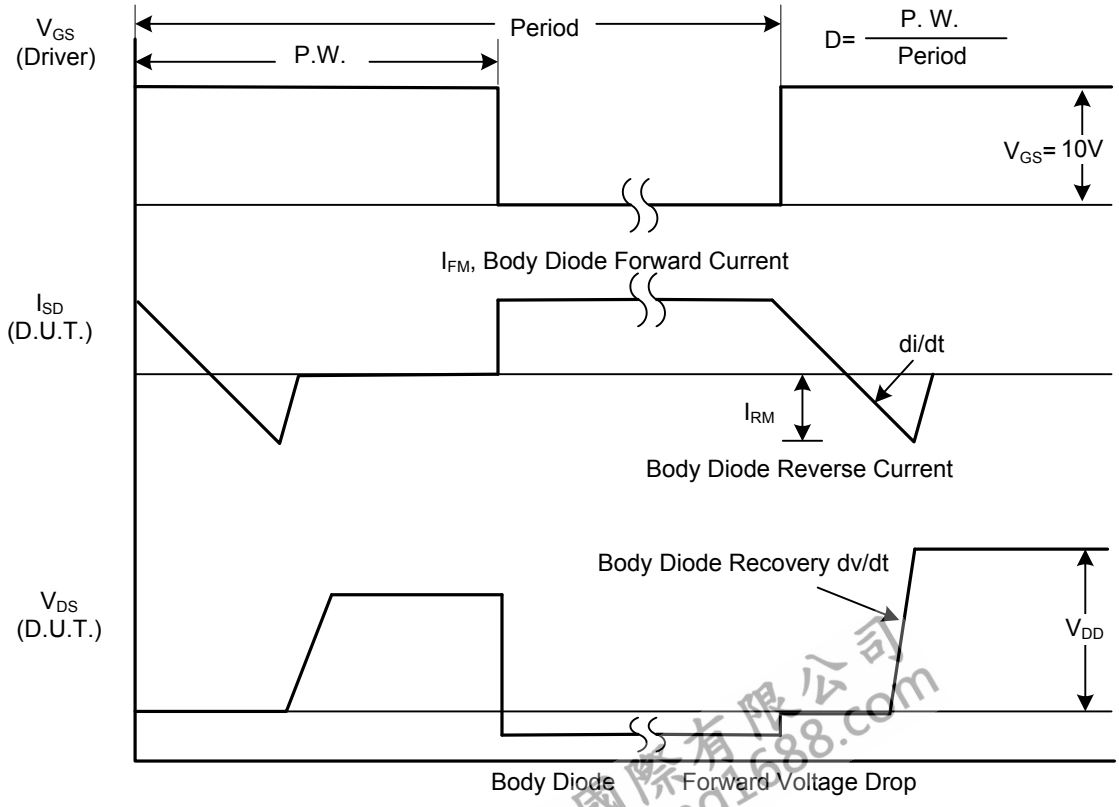
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	V_{GS}=0V, I_D=250μA	650			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=650V, V_{GS}=0V			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS}=30V, V_{DS}=0V			100	nA
	Reverse		V_{GS}=-30V, V_{DS}=0V			-100	
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	2.5		4.5	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=2.0A			2.1	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C_{ISS}	V_{GS}=0V, V_{DS}=25V, f=1.0MHz		220		pF
Output Capacitance		C_{OSS}			170		pF
Reverse Transfer Capacitance		C_{RSS}			16		pF
SWITCHING CHARACTERISTICS							
Total Gate Charge (Note 1)		Q_G	V_{DS}=300V, V_{GS}=10V, I_D=4.0A, I_G=5mA (Note 1, 2)		16.5		nC
Gate to Source Charge		Q_{GS}			5.4		nC
Gate to Drain Charge		Q_{GD}			6.4		nC
Turn-ON Delay Time (Note 1)		$t_{D(ON)}$	V_{DD}=200V, V_{GS}=10V, I_D=4.0A, R_G=25Ω (Note 1, 2)		7.2		ns
Rise Time		t_R			16.5		ns
Turn-OFF Delay Time		$t_{D(OFF)}$			32		ns
Fall-Time		t_F			28		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				4.0	A
Maximum Body-Diode Pulsed Current		I_{SM}				20	A
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I_S=4.0A, V_{GS}=0V			1.4	V
Body Diode Reverse Recovery Time (Note 1)		t_{rr}	I_S=4.0A, V_{GS}=0V, dI_F/dt=100A/μs		260		ns
Body Diode Reverse Recovery Charge		Q_{rr}			1.76		μC

Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%.
2. Essentially independent of operating temperature.

■ TEST CIRCUITS AND WAVEFORMS

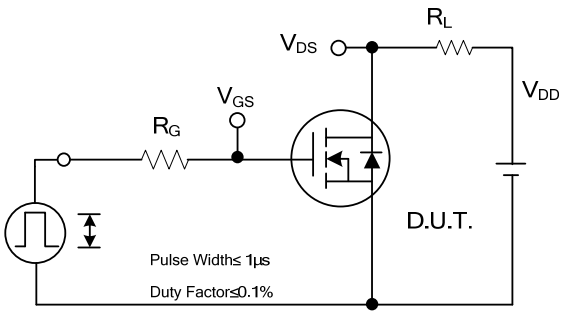


Peak Diode Recovery dv/dt Test Circuit

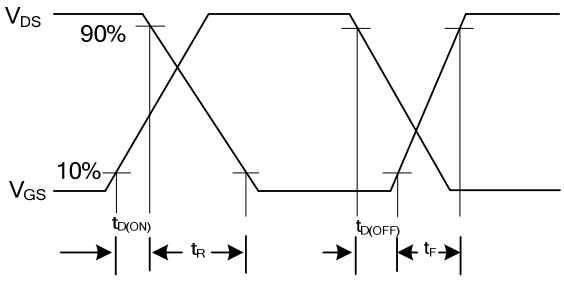


Peak Diode Recovery dv/dt Waveforms

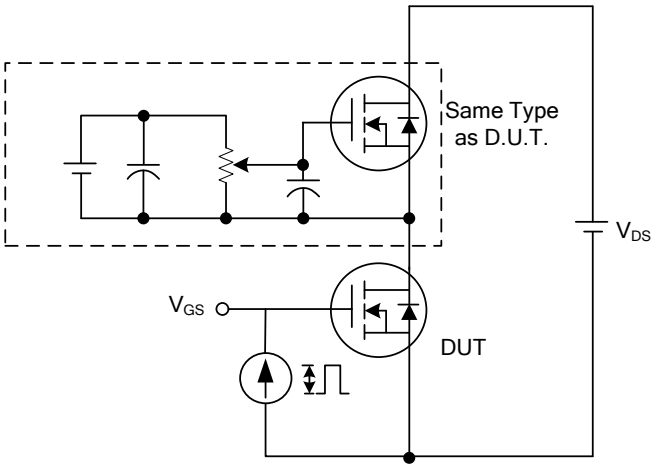
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



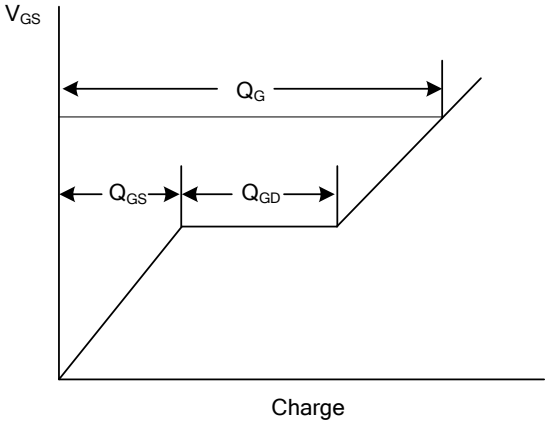
Switching Test Circuit



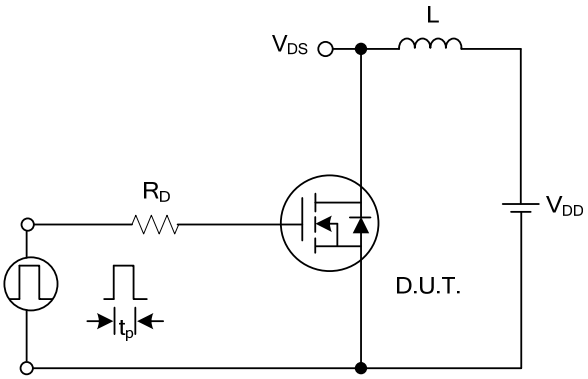
Switching Waveforms



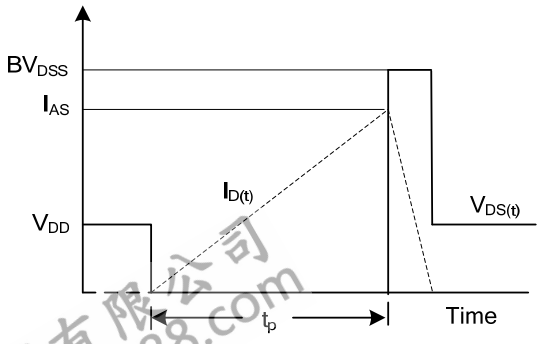
Gate Charge Test Circuit



Gate Charge Waveform



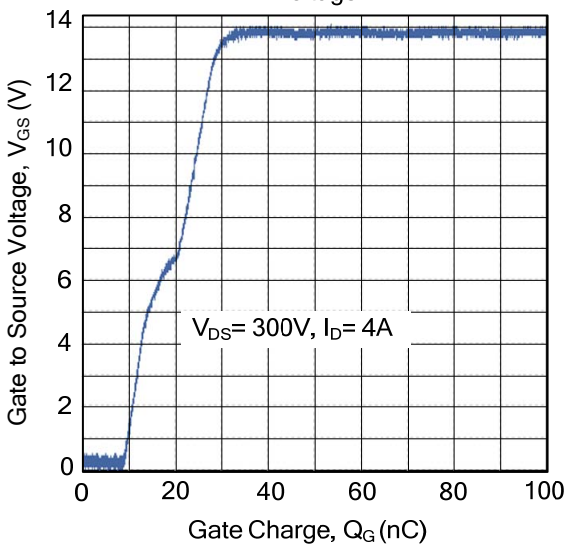
Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS

Gate Charge vs. Gate to Source Voltage



Capacitance Characteristics